Serial No.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Thomas Watkins Lloyd	et al.	Group Art Unit:										
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Service as first cla	this correspondence is being deposes mail in an envelope addressen, D.C. 20231, on the date indicated	osited with the United States Postal d to: Assistant Commissioner for d below.										
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An original and two (2) copies of this document are enclosed.

Respectfully submitted,

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